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ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18
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Title of Invention

METHODS AND SYSTEMS FOR INSPECTION OF AN ENTIRE WAFER SURFACE USING MULTIPLE DETECTION CHANNELS

Application Number:

10/663603

Confirmation Number:

3534

First Named Applicant:

Lionel Kuhlmann

Attorney Docket Number: 5589-06100

FEDD 00400

Search string:

(6271916 or 6204917 or 6559938 or 6201601 or 6538730 or 6509965 or 6507394 or 6356346 or 6020957 or 5355212 or 6407809 or 6515742 or 6496256 or 6034776 or 5999266 or 5801824 or 5623340 or 5604585 or 5585916 or 4632546

or 20030030050 or 20030030795 or 20020149765 or 20020145732 or

20010028454).pn.

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Note: Applicant is not required to submit a paper copy of cited US Patent Documents

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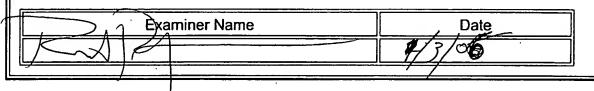
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Signature



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ATY. DKT. NO. 5589-06100 Form PTO-1449 (modified) SERIAL NO. 10/663,603 List of Patents and Publications APPLICANT: Kuhlmann et al. **GROUP: 2877** For Applicant's Information **Disclosure Statement** FILING DATE: September 16, 2003 (Use several sheets if necessary) **U.S. PATENT DOCUMENTS** EXAM. REF. **DOCUMENT NUMBER** DATE NAME CLASS SUB FILING DATE IF **APPROPRIATE INITIALS CLASS** DES. FOREIGN PATENT DOCUMENTS TRANSLATION **COUNTRY** EXAM. REF. **DOCUMENT NUMBER** DATE CLASS **SUB** YES/NO **INITIALS** DES. **CLASS** P 10/1997 **A1** 97/39339 WO 7/1997 JP **A2** 9-191037 OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) DATE CONSIDERED:

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